2SB1398

Silicon PNP epitaxial planar type

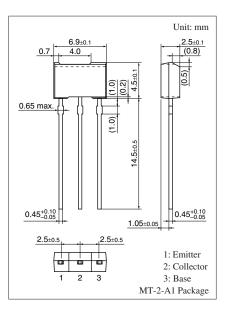
For low-frequency power amplification

Features

- Low collector-emitter saturation voltage $V_{CE(sat)}$
- Large collector current I_C
- Allowing supply with the radial taping

Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V _{CBO}	-30	V
Collector-emitter voltage (Base open)	V _{CEO}	-25	V
Emitter-base voltage (Collector open)	V _{EBO}	-7	V
Collector current	I _C	-5	А
Peak collector current	I _{CP}	-8	А
Collector power dissipation *	P _C	1	W
Junction temperature	Tj	150	°C
Storage temperature	T _{stg}	-55 to +150	°C



Note) *: Print circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

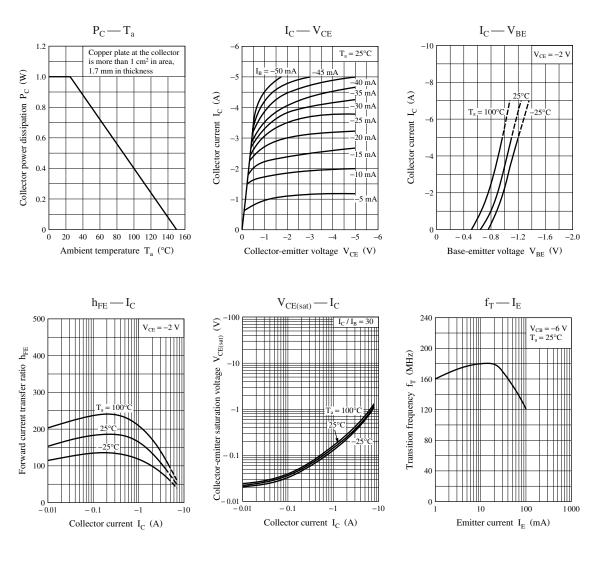
Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

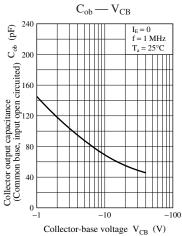
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V _{CEO}	$I_{\rm C} = -1 {\rm mA}, I_{\rm B} = 0$	-25			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_E = -10 \ \mu A, \ I_C = 0$	-7			V
Collector-base cutoff current (Emitter open)	I _{CBO}	$V_{CB} = -10 \text{ V}, I_E = 0$			-100	nA
Emitter-base cutoff current (Collector open)	I _{EBO}	$V_{EB} = -5 V, I_C = 0$			-100	nA
Forward current transfer ratio *1, 2	h _{FE}	$V_{CE} = -2 V, I_C = -2 A$	90		205	_
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_{\rm C} = -3$ A, $I_{\rm B} = -0.1$ A			-1	V
Transition frequency	f _T	$V_{CB} = -6 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -20 \text{ V}, I_E = 0, f = 1 \text{ MHz}$			85	pF
(Common base, input open circuited)						

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. *1: Pulse measurement

*2: Kalik classification					
Rank	Р	Q			
h _{FE}	90 to 135	120 to 205			





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